

Notice of References Cited	Application/Control No. 10/709,529	Applicant(s)/Patent Under Reexamination NOWLAN ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
	B	US-			
	C	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	W	Breitenstein et al.; "Imaging the Local Forward Current Density of Solar Cells By Dynamic Precision Contact Thermography"; 1st WCPEC, Dec. 5-9, 1994, Hawaii; pages 1633-1636.
	X	Nowlan et al., "Automated Solar Cell Assembly Teamed Process Research, National Renewable Energy Laboratory (NREL)(Feb. 1996)

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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